

**FOCUSED ION BEAM PROCESS
FOR REMOVAL OF COPPER METAL**

ABSTRACT OF THE DISCLOSURE

A process for milling copper metal from a substrate having an exposed copper surface includes absorbing a halogen gas onto the exposed copper surface to generate reaction products of copper and the halogen gas; removing unreacted halogen gas from the surface; and directing a focused ion beam onto the surface to selectively remove a portion of the surface comprising the reaction products.

TOP SECRET - DEFENSE